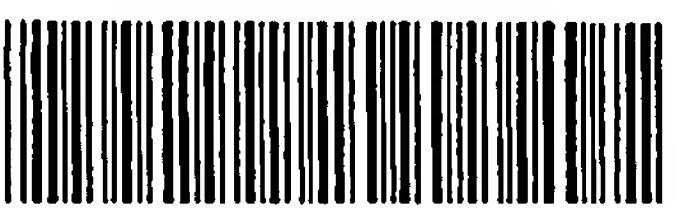


<b>Search Notes</b> 				Application/Control No.	Applicant(s)/Patent under Reexamination
				10/815,516	CAIN ET AL.
				Examiner	Art Unit
				Alan S. Chen	2182
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>	
Class	Subclass	Date	Examiner		DATE
710	15	10/10/2006	ASC	(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	10/10/2006
	16				
	17				
	18				
	19				
↓	62	↓	↓	limited class search updated EAST	4/31/07
<b>INTERFERENCE SEARCHED</b>					
Class	Subclass	Date	Examiner		